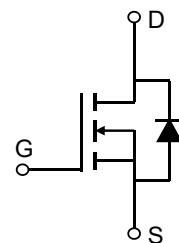


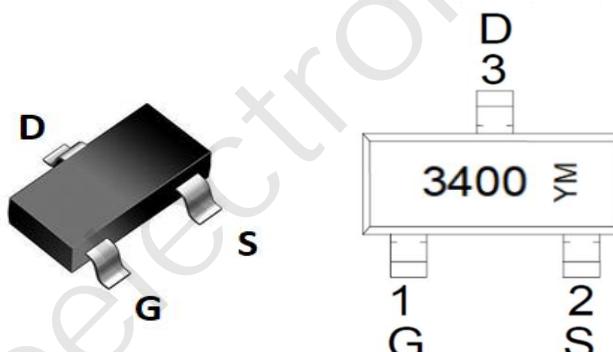
Description

Features

- 30V, 5.8A
- $R_{DS(ON)}$ Typ = 20.5mΩ @ V_{GS} = 10V
- $R_{DS(ON)}$ Typ = 22mΩ @ V_{GS} = 4.5V
- $R_{DS(ON)}$ Typ = 26mΩ @ V_{GS} = 2.5V
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free



Schematic Diagram



Marking and Pin Assignment

Package Marking and Ordering Information

Device	Marking	Package	Outline	Reel Size	Reel (pcs)	Per Carton (pcs)
CRMJTU3400A	3400	SOT-23-3L	TAPING	7"	3000	120000

Absolute Maximum Ratings (@ $T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Units
V_{DS}	Drain-to-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 12	V
I_D	Continuous Drain Current $T_A = 25^\circ\text{C}$	5.8	A
	$T_A = 100^\circ\text{C}$	3.48	A
I_{DM}	Pulsed Drain Current ⁽¹⁾	23.2	A
P_D	Power Dissipation $T_A = 25^\circ\text{C}$	1.56	W
R_{QJA}	Thermal Resistance, Junction to Ambient ⁽²⁾	80	°C/W
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150	°C

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 12\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.5	0.9	1.5	V
		$V_{GS} = 10\text{V}, I_D = 5.8\text{A}$	-	20.5	27	$\text{m}\Omega$
	Static Drain-Source ON-Resistance ⁽³⁾	$V_{GS} = 4.5\text{V}, I_D = 5\text{A}$	-	22	29	$\text{m}\Omega$
		$V_{GS} = 2.5\text{V}, I_D = 4\text{A}$	-	26	35	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 15\text{V}, f = 1\text{MHz}$	-	816	-	pF
C_{oss}	Output Capacitance		-	60	-	pF
C_{rss}	Reverse Transfer Capacitance		-	50	-	pF
Q_g	Total Gate Charge	$V_{GS} = 0 \text{ to } 4.5\text{V}$ $V_{DS} = 15\text{V}, I_D = 5.8\text{A}$	-	8	-	nC
Q_{gs}	Gate Source Charge		-	1.6	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	2.1	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On DelayTime	$V_{GS} = 10\text{V}, V_{DD} = 15\text{V}$ $I_D = 5.8\text{A}, R_{\text{GEN}} = 3\Omega$	-	5	-	ns
t_r	Turn-On Rise Time		-	7	-	ns
$t_{d(off)}$	Turn-Off DelayTime		-	40	-	ns
t_f	Turn-Off Fall Time		-	6	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	$V_{GS} = 0\text{V}, I_S = 5.8\text{A}$	-	-	5.8	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	23.2	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 5.8\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F = 3\text{A}, dI/dt = 100\text{A}/\mu\text{s}$	-	8.4	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	3.3	-	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

2. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.

Test Circuit

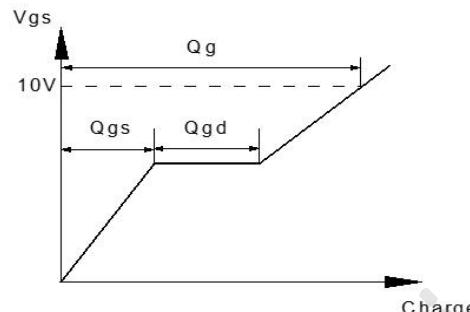
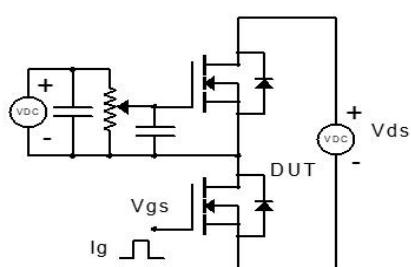


Figure 1: Gate Charge Test Circuit & Waveform

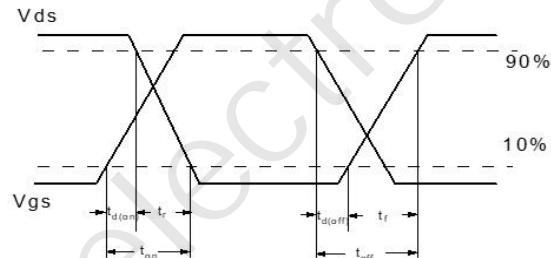
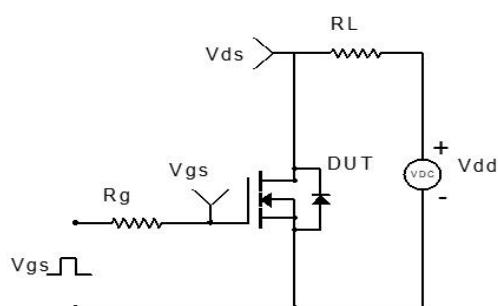


Figure 2: Resistive Switching Test Circuit & Waveform

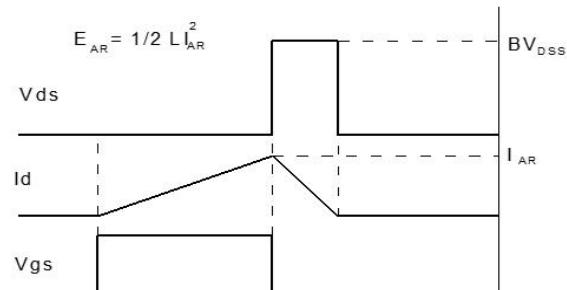
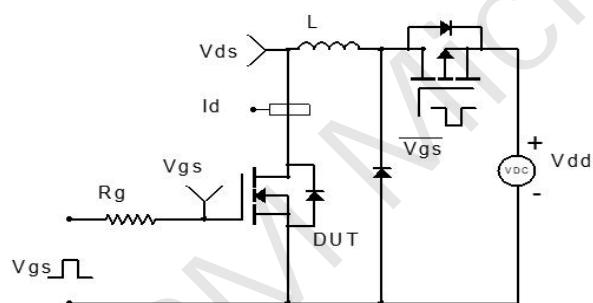


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

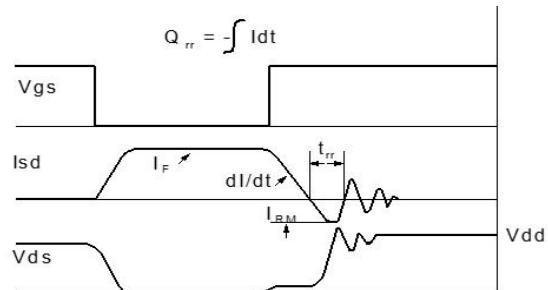
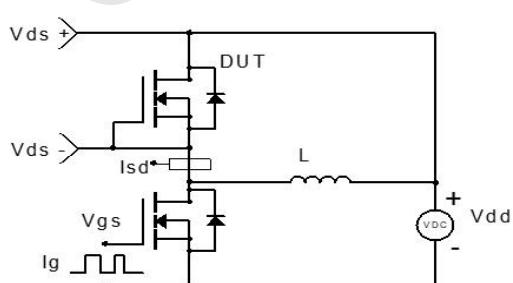
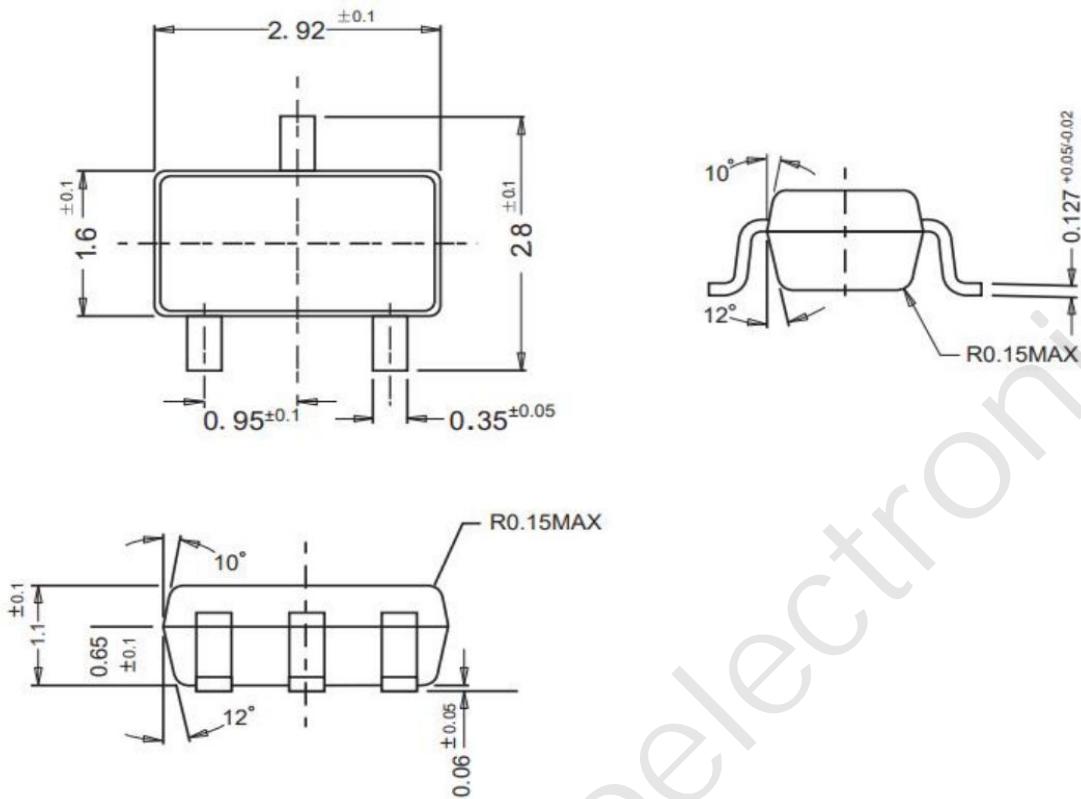


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(SOT-23-3L)



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